

Advanced Technology Institute

Faculty of Engineering and Physical Sciences

Vlad Stolojan

University of Surrey

Guildford GU2 7XH

www.surrey.ac.uk



Concentratori parabolici pentru spectroscopie Raman



Dr Vlad Stolojan
Lecturer, RCUK Fellow

Sumar

- Institutul de Tehnologie Avansata
- CV
- Microscopie electronica
- Concentrori parabolici





Colective de cercetare

Nano-electronica

- Componente avansate bazate pe Si.
- Circuite si componente de microunde.
- Electronica pe scara mare, inclusiv celule solare si panouri de afisaj.
- nanoelectronica, inclusiv nanotuburi de carbon

Fotonica

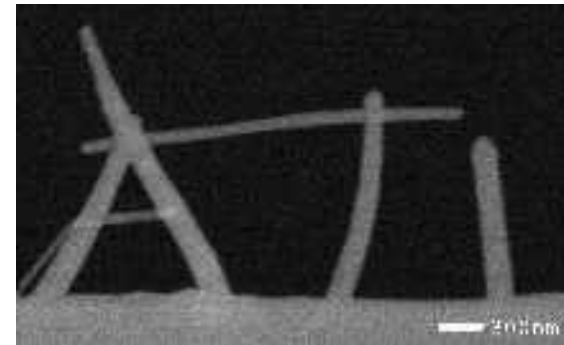
- Materiale si componente optoelectronice
- Photonica bazata pe Si
- Spintronica si analiza dinamica ultra-rapida
- Sensori optici

Centrul de acceleratori de ioni

- implantare ultra-precisa
- Modificare de materiale
- Analiza cu ioni, inclusiv studii arheologice si criminalistice.
- Aplicatii bio-medicale

Theory and Advanced Computation

- Cuantica computationala
- Modelare la scara atomica



- Universitatea East Anglia (1996) BSc
- Universitatea Cambridge (2000) PhD
 - Nanochimia interfețelor cristaline in fier
- Universitatea Cambridge -postdoc
 - holografie-tomografie componente magnetice
- Universitatea Surrey – postdoc, research fellow, lecturer
 - microscopie electronica si cu ioni + spectroscopie
(TEM, SEM, STEM, FIB + EELS, EDX)
 - materiale ceramice, funcționale, nanomateriale (QD, nanotuburi, mecanisme de formare etc), adezivi, bio (celule, viruși)

Electroni: $\lambda \sim \text{pm}$. Aberație sferică – rezoluție nm-0.5Å (cu ochelari)

- TEM (transmisie), SEM (scanare – reflexie), STEM (scanare transmisie)
 - imaginea = amplitudine + fază
- Spectroscopie: EELS (electron energy-loss spectroscopy), EDX (energy-dispersive X ray spectroscopy *sau* EDS)
 - EELS: energia pierdută de electronii ce au traversat materialul
 - EDX: raze X emise ca urmare a pierderii de energie de electroni (tranzitii induse in atomii materialului, urmate de relaxarea electronilor).

Informații despre structura electronica cu rezoluție sub-nanometrică.

Philips(FEI) CM200 TEM



Imagini formate in paralel:
Rezoluție (interferență) $>1.8\text{\AA}$
diametrul fascicului de $e^- \sim 10\text{nm}$.
LaB₆, 80-200keV
EDX, EELS

Hitachi HD2300A STEM

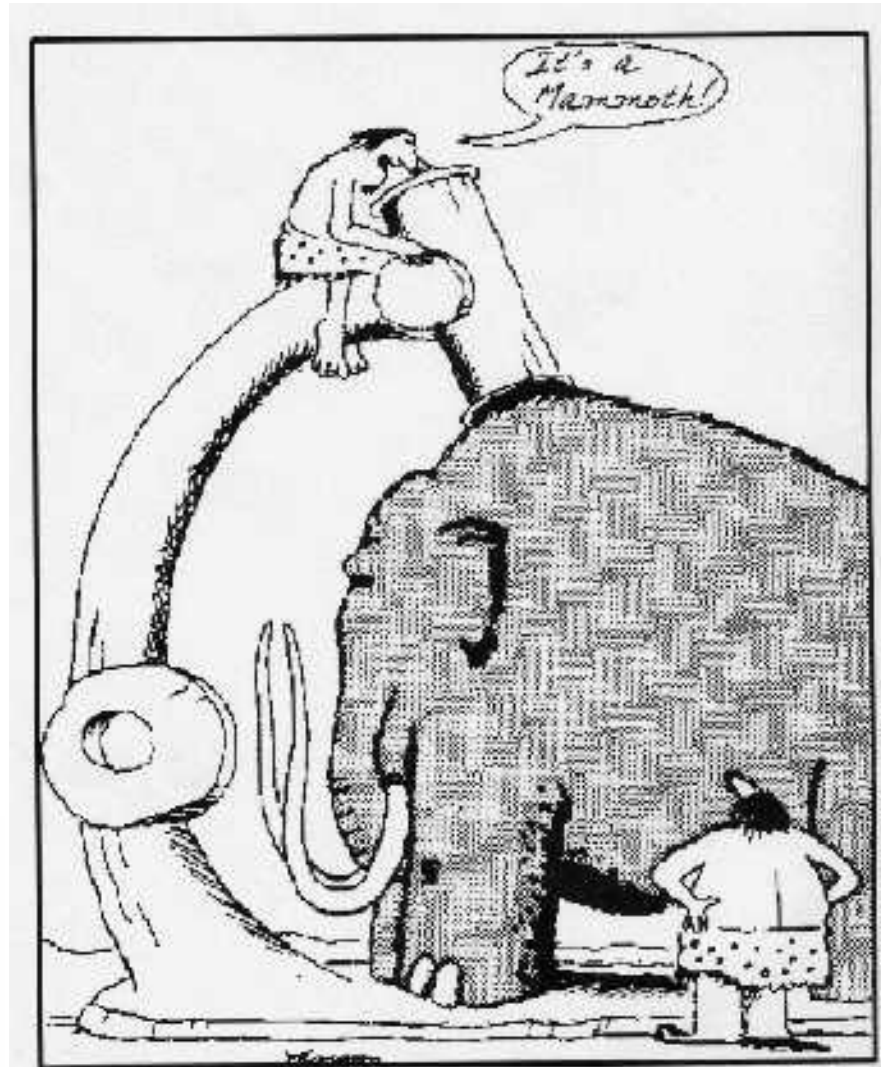


Imagini formate pixel cu pixel:
diametrul fascicului de $e^- >2.5\text{\AA}$

Schottky, 120keV, 200keV

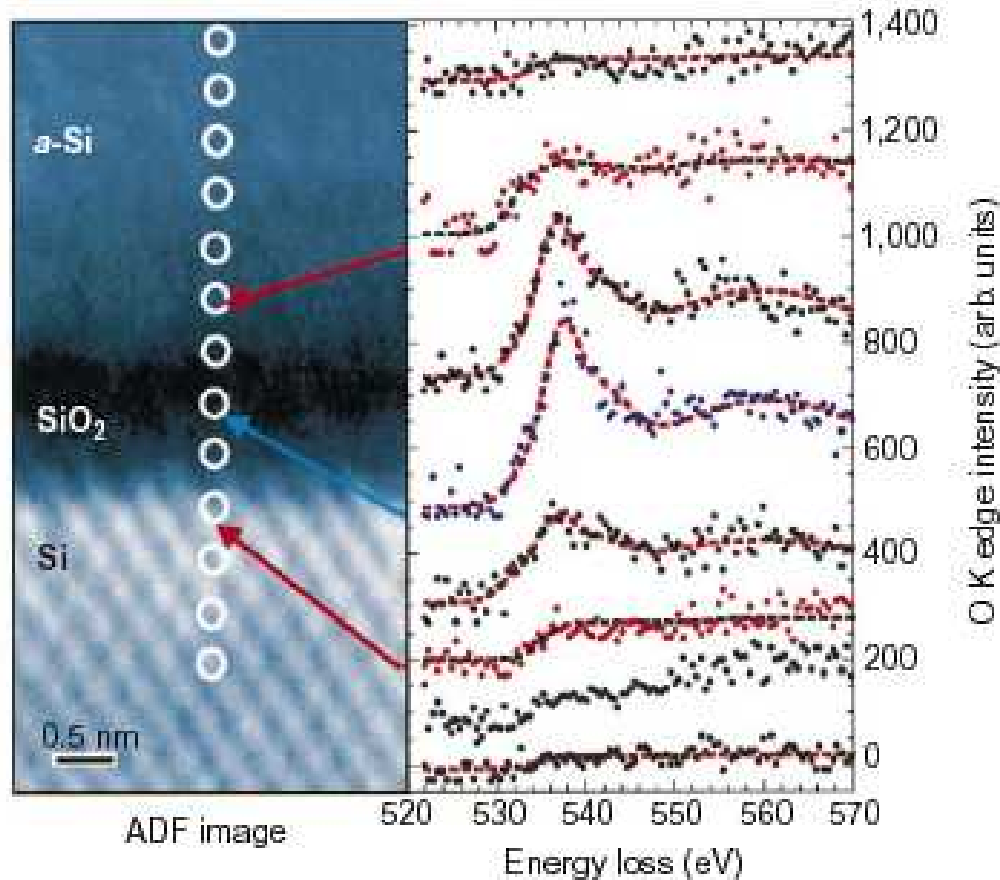
EDX, EELS

Microscopie- o viziune alternativa



Early Microscope

DA Muller et al Nature 399 (1999) 758

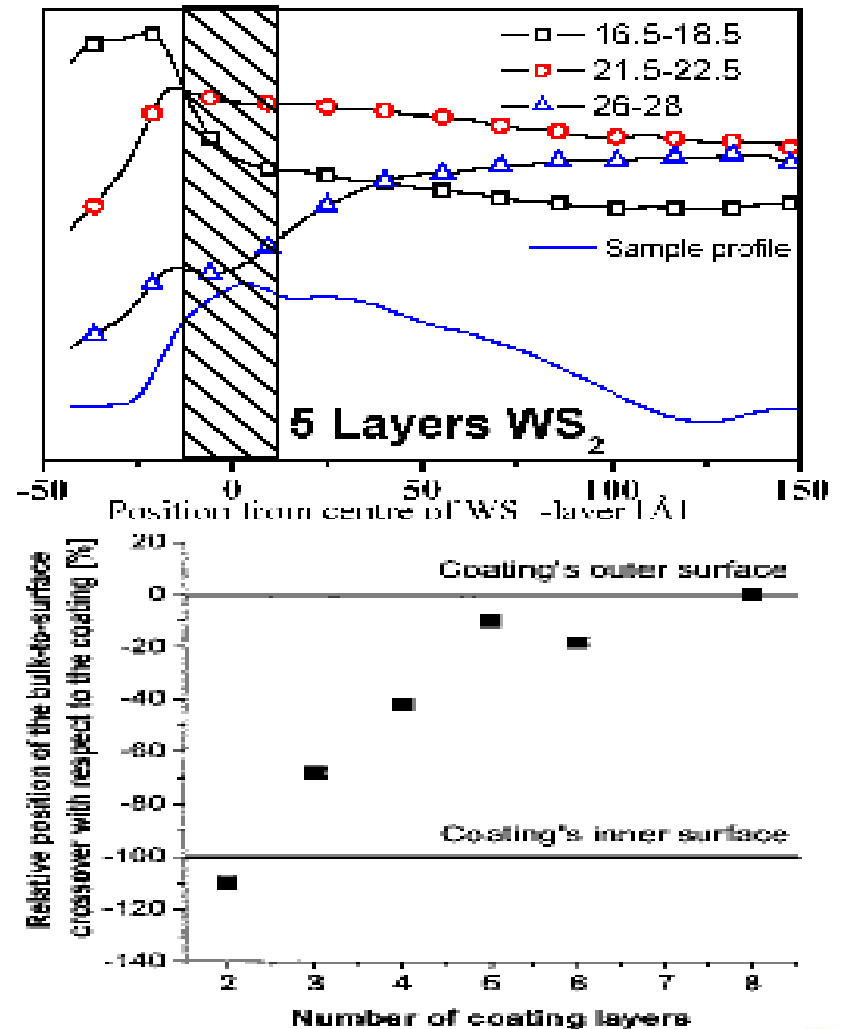
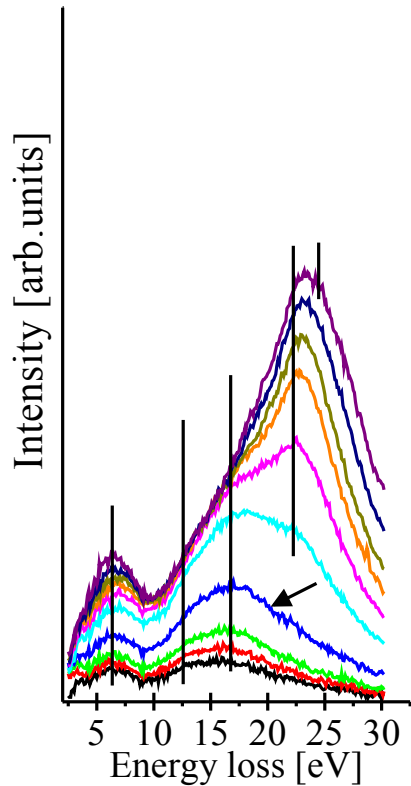
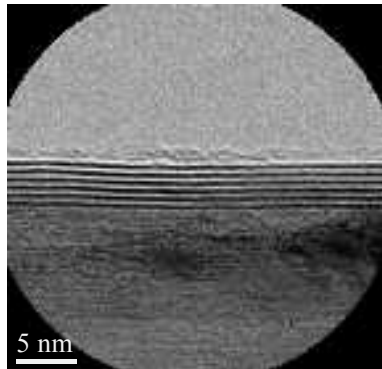


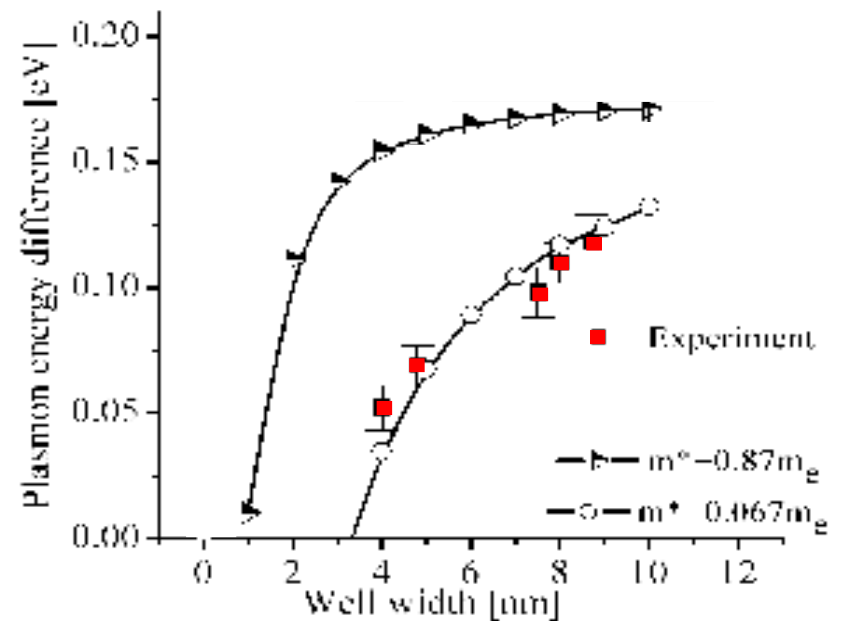
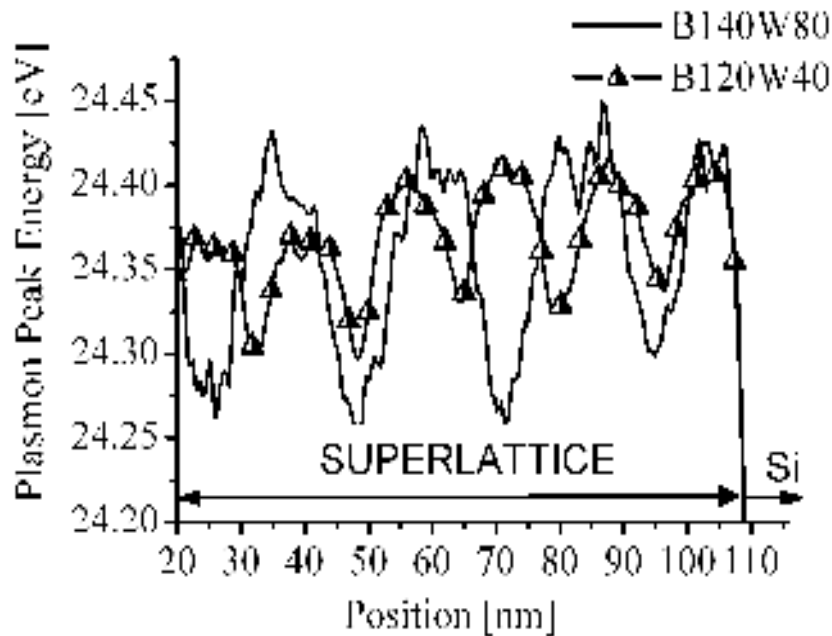
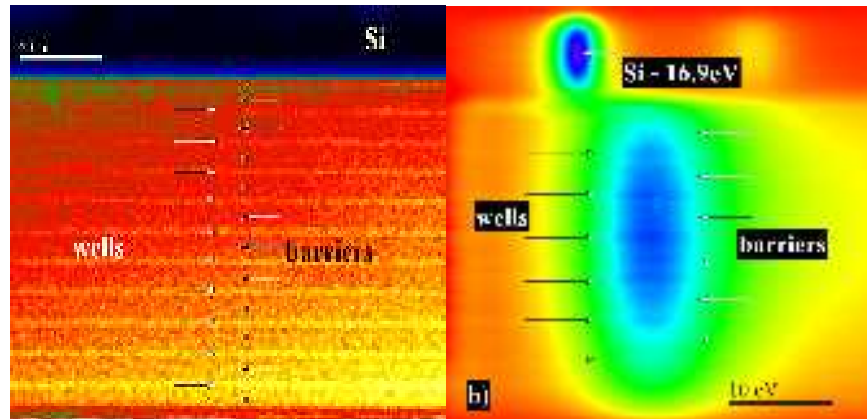
Limita fizică a Si – minimum 4 planuri atomice!

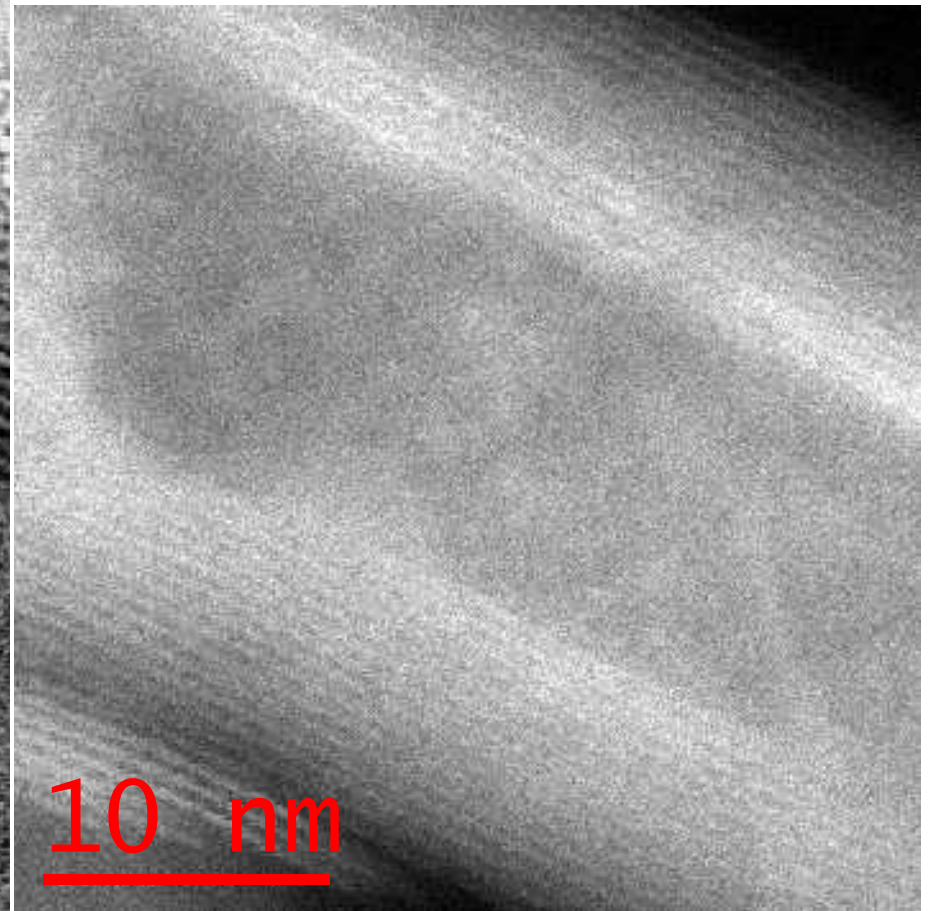
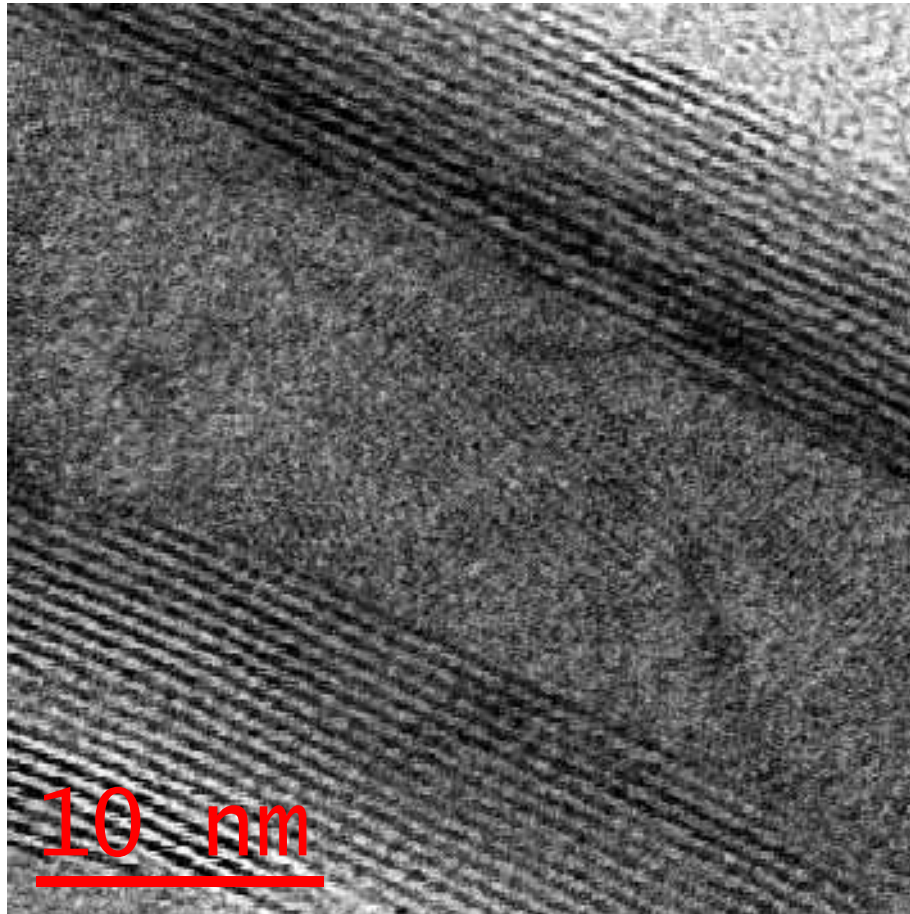
- Oscilații colective ale electronilor: culori metalice, vitralii, transmisii in afara ionosferei.
- Cel mai probabil mod de interacție cu electronii. Energie si impuls suficiente pentru a interacționa cu plasmonii in orice material. Moduri de oscilație delocalizate!
- Plasmoni de suprafață, interfață (moduri de oscilație cu dimensionalitate redusă.
- Plasmonii de interfață/suprafață ecranează interiorul materialelor: i.e. interacțiile nu sunt aditive = localizare.



Nanotuburi de carbon invelite in WS₂

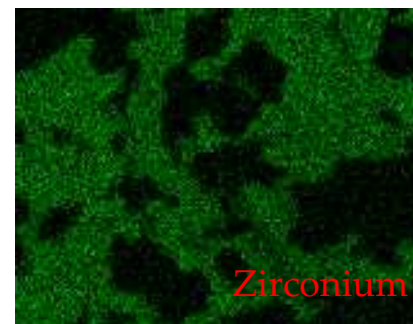
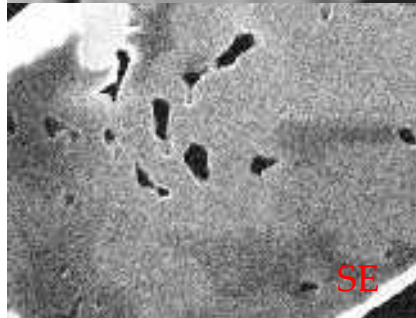
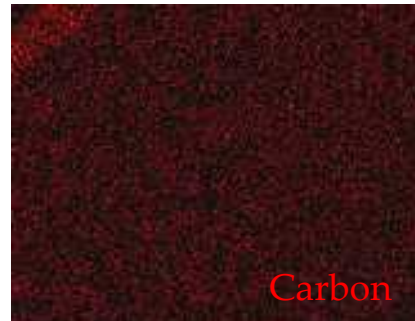
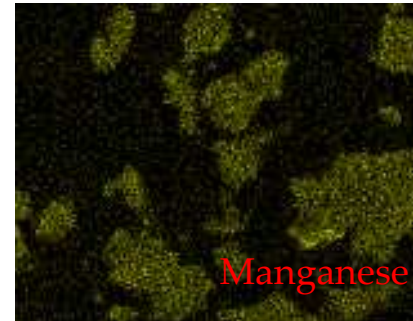
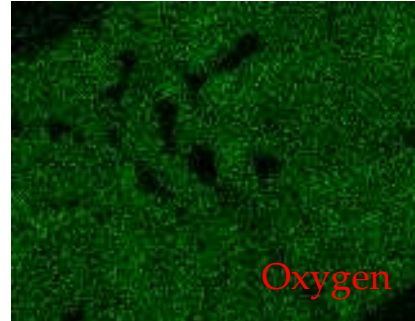
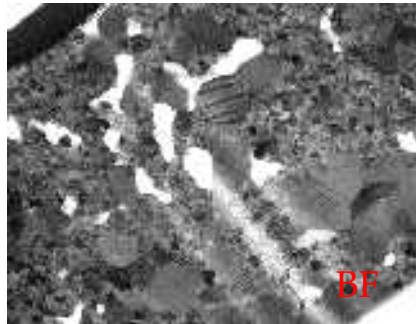


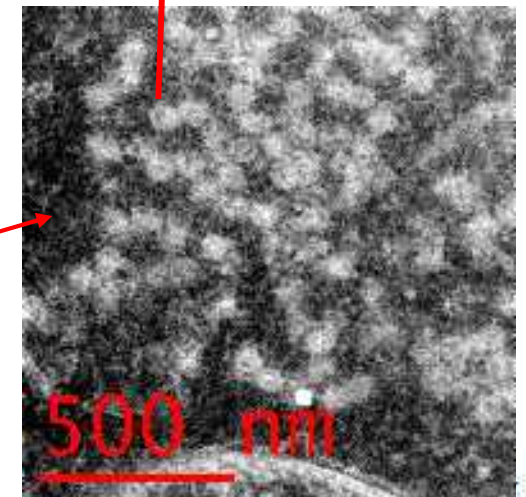
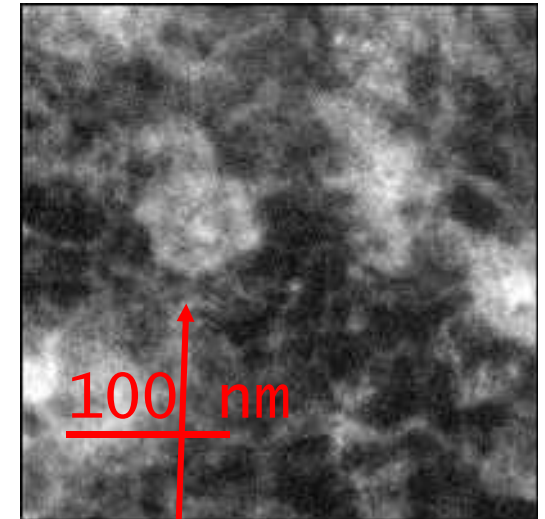
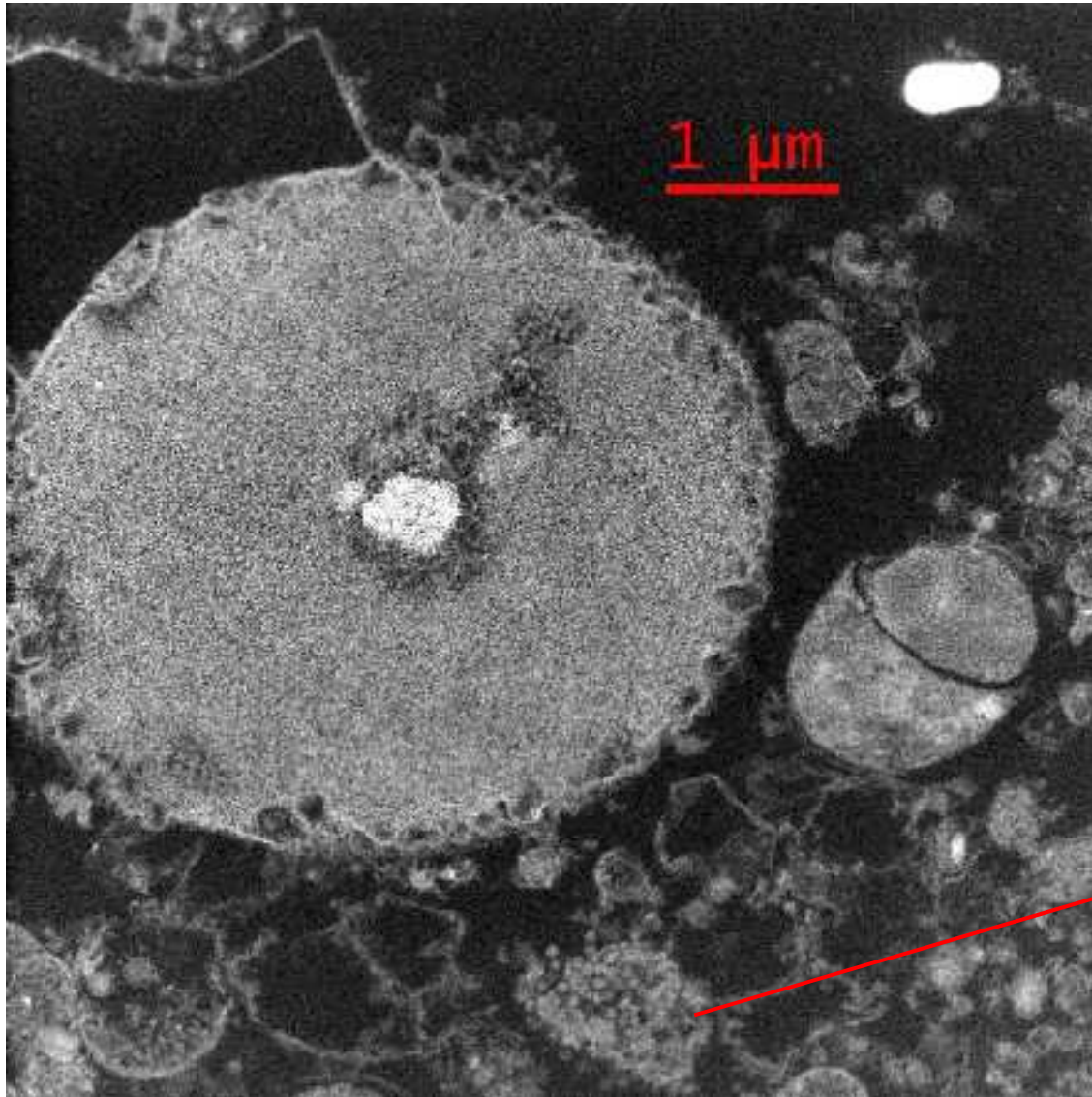




$I_{\text{HAADF}} \propto \text{density} \times \text{thickness} \times Z^2$

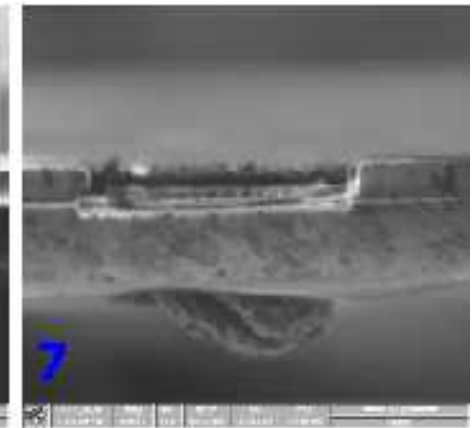
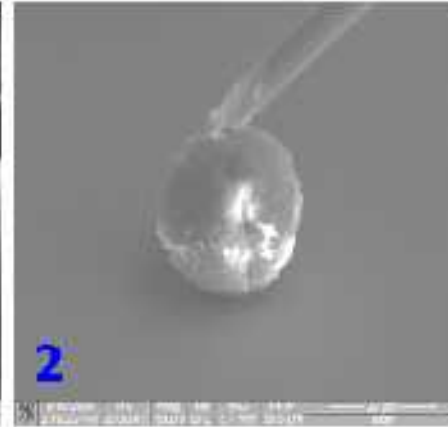
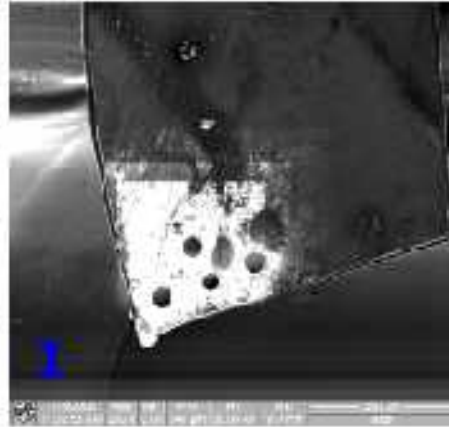
STEM

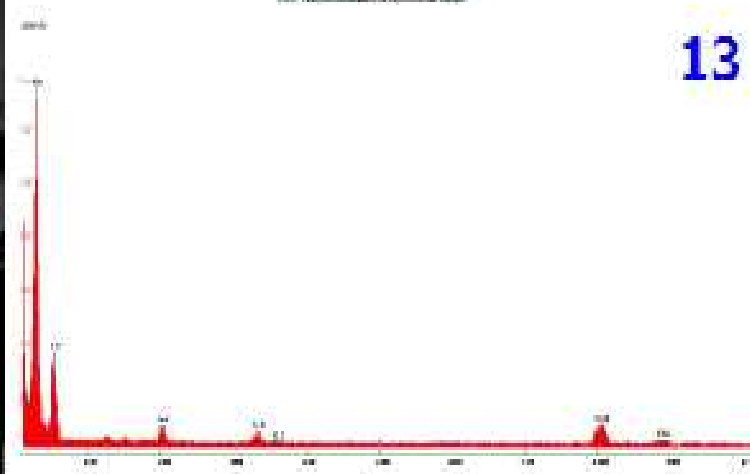
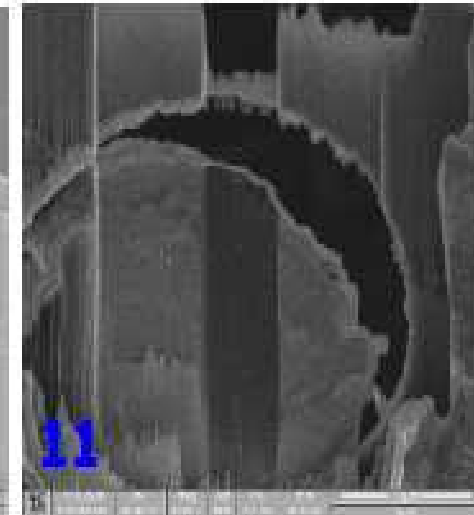
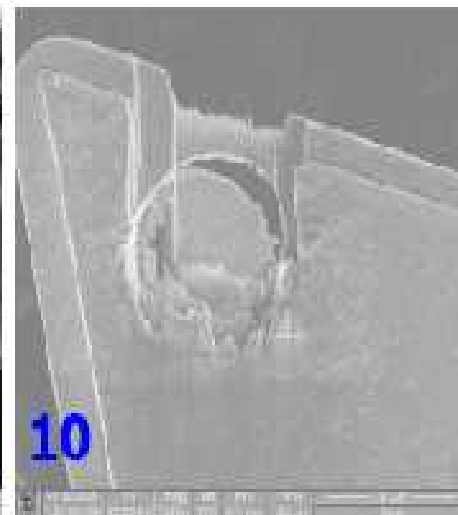
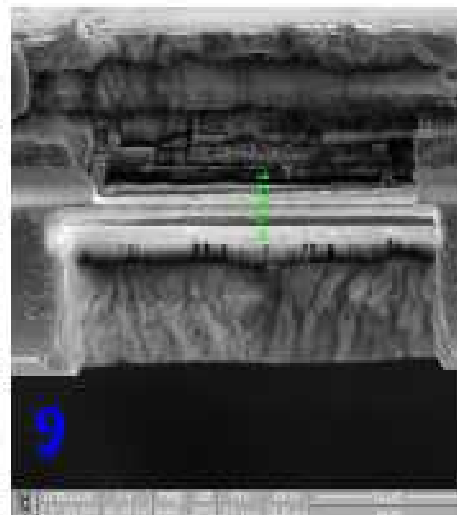
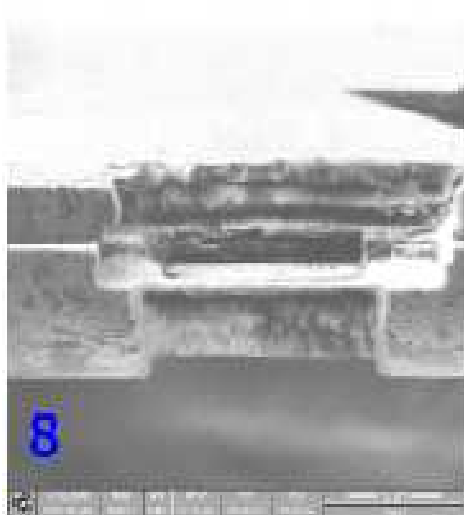






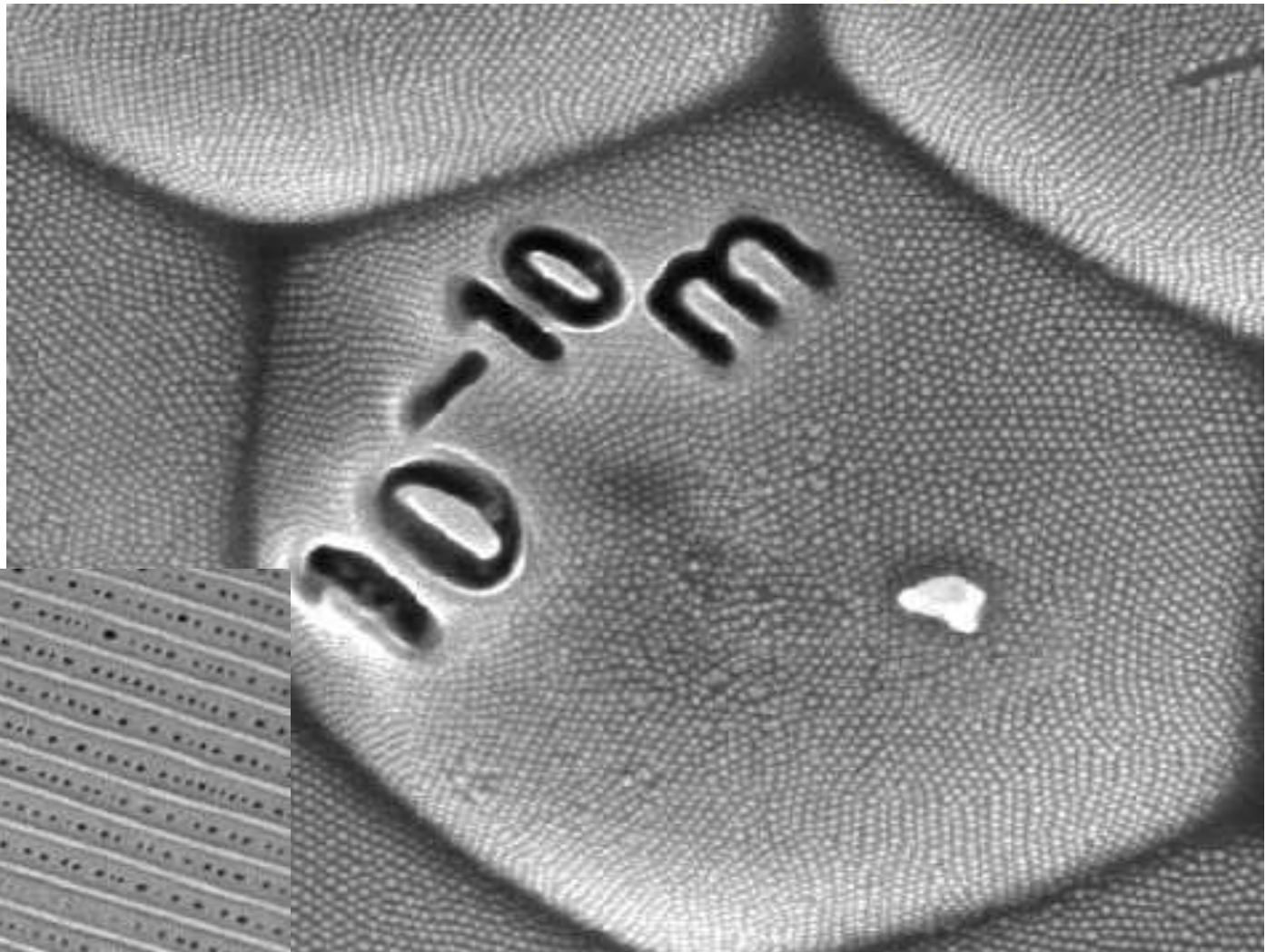
Microscopul cu ioni





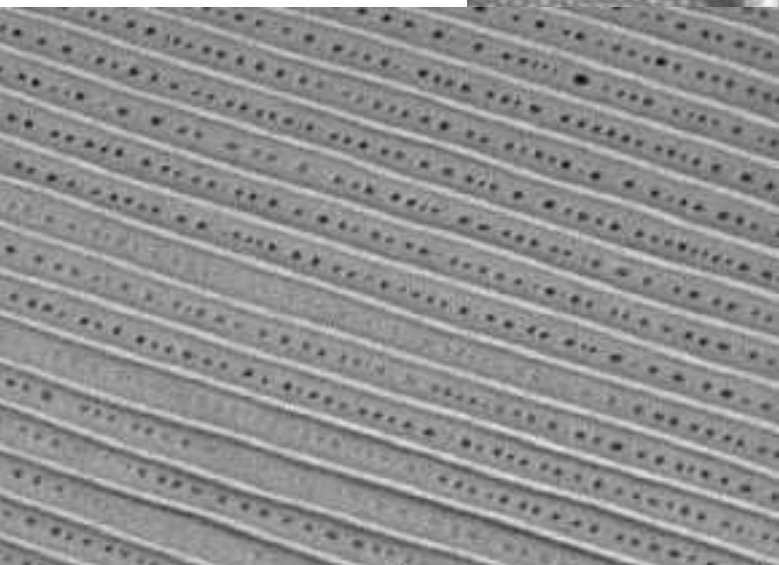


7/22/2009	HV	Spot	Mag	Det	WD	HFW	—500.0µm—
12:12:48 PM	30.0 kV	3.0	108x	ETD	9.7 mm	2.51 mm	University of Surrey

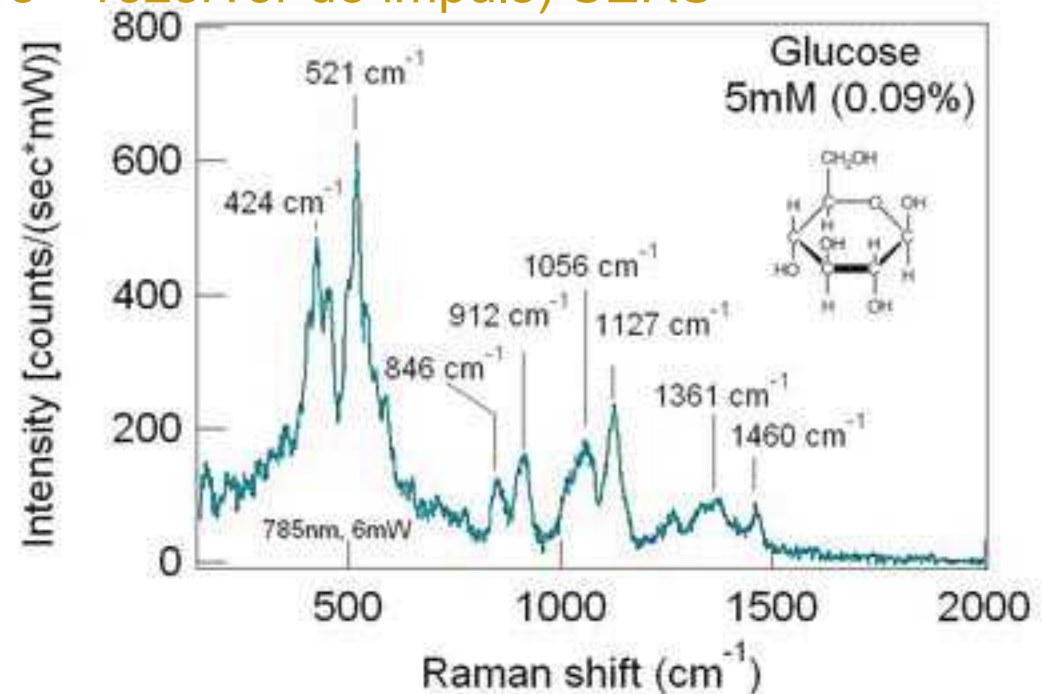


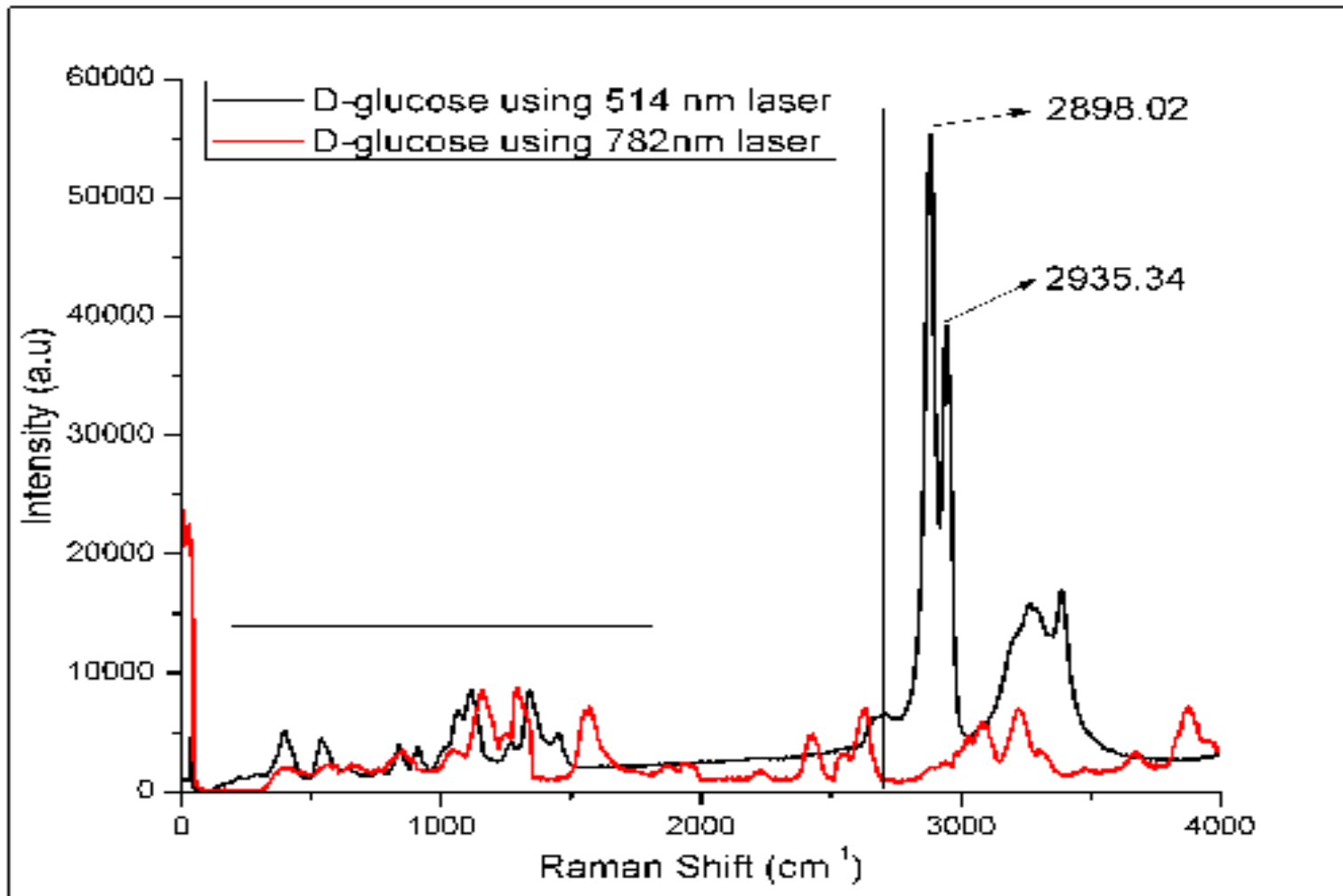
Spot	Mag	Det	WD	HPW
3.0	13878x	ETD	9.5 mm	19.43 μ m

5.0 μ m
University of Surrey

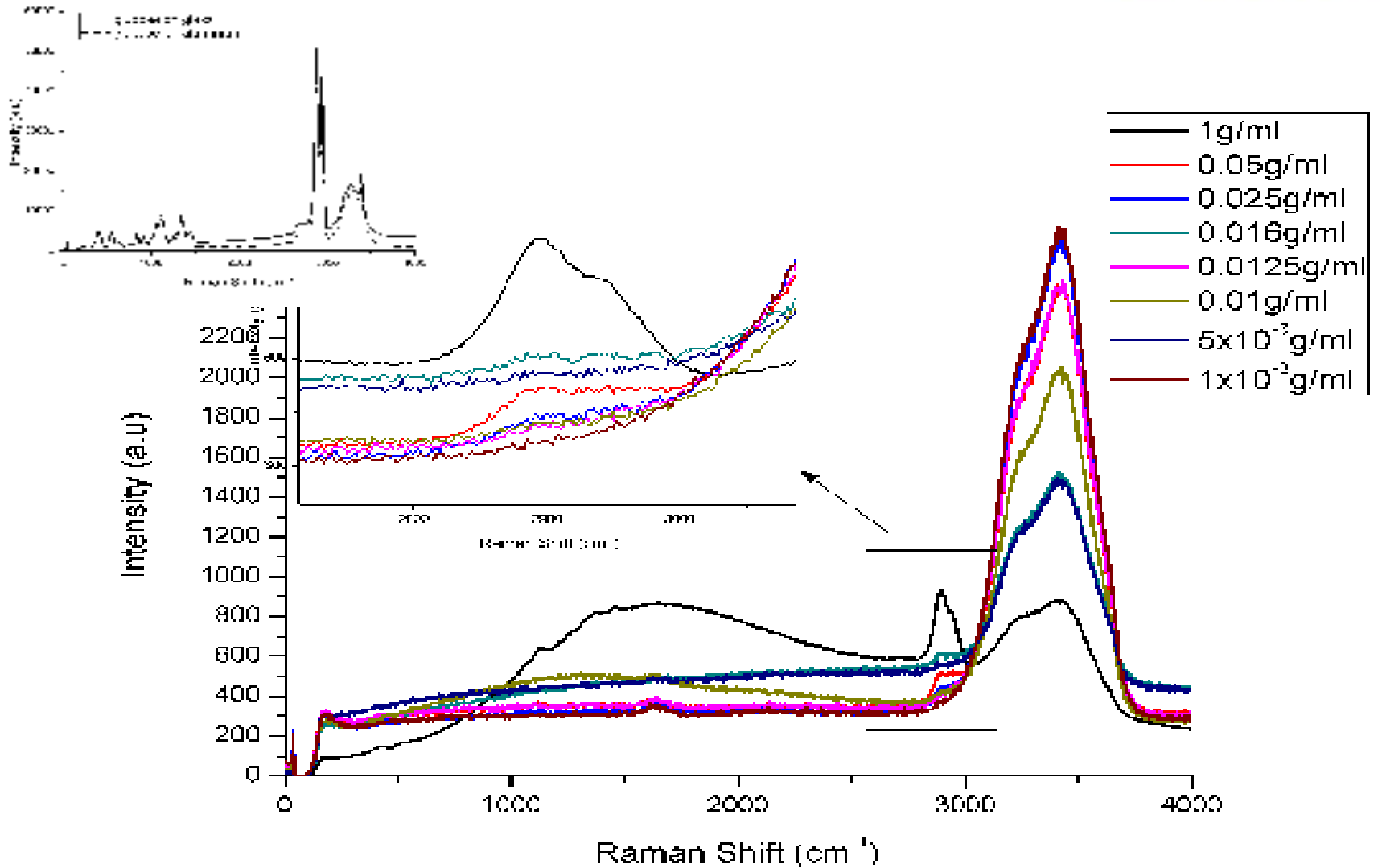


- Interacție inelastică a radiației cu substratul (relfectiv)
- Stokes sau Anti-Stokes
 - regula de selecție: schimbarea polarizării
- Probabilitate $\sim 1:10^4$
 - plasmoni de suprafață/interfață modifică această probabilitate (i.e. polarizare – rezervor de impuls) SERS
- Tehnică non-contact
- 'ne-destructivă'

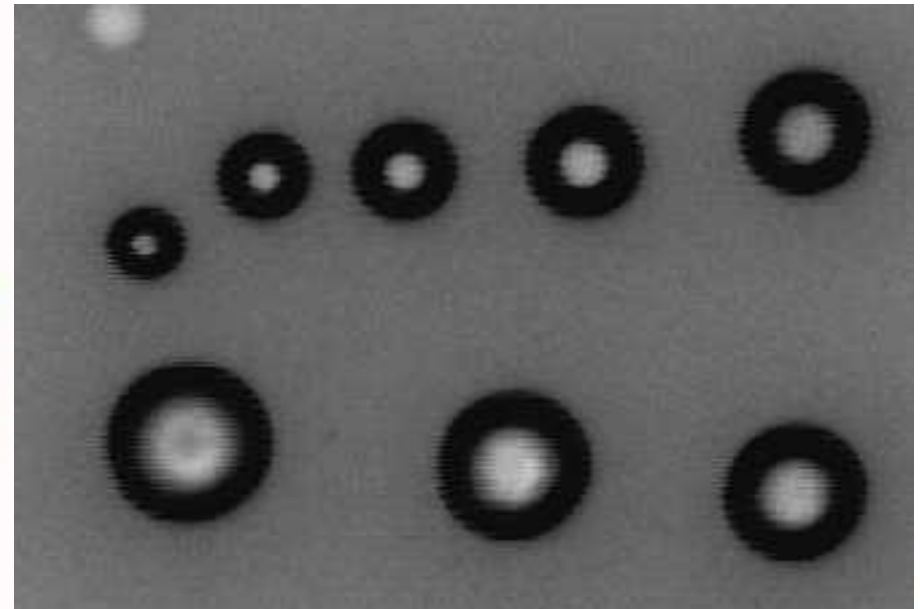
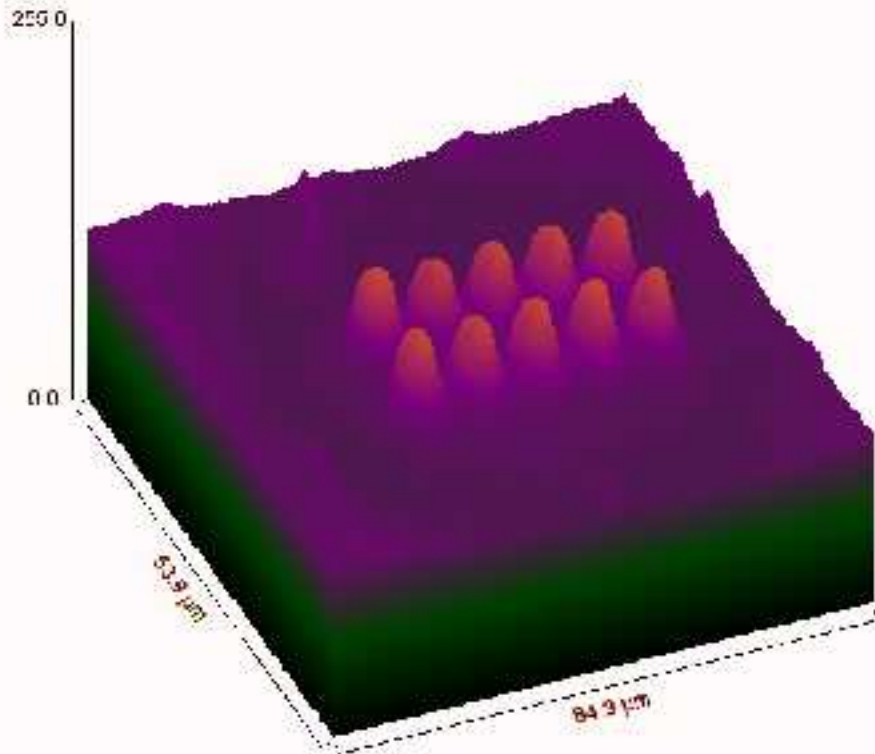
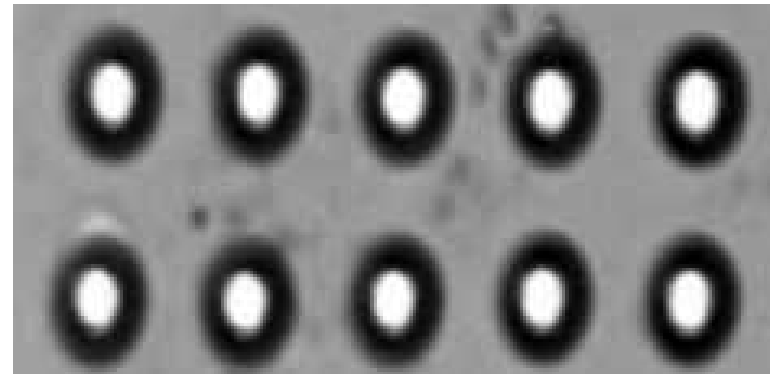
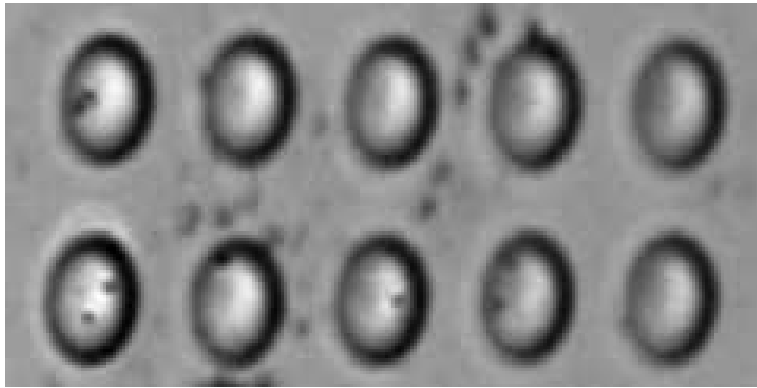




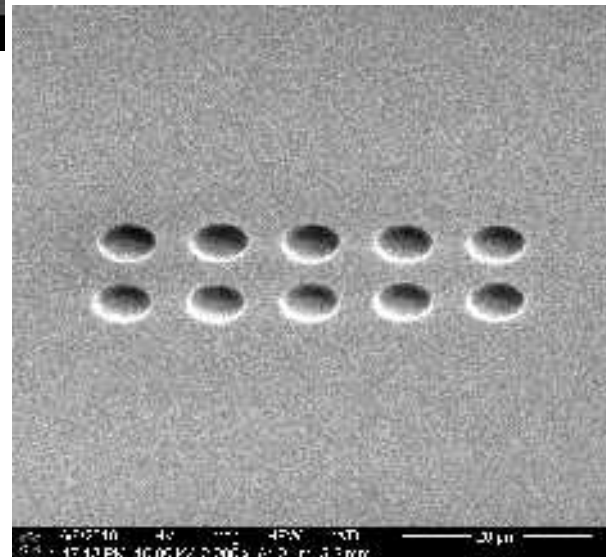
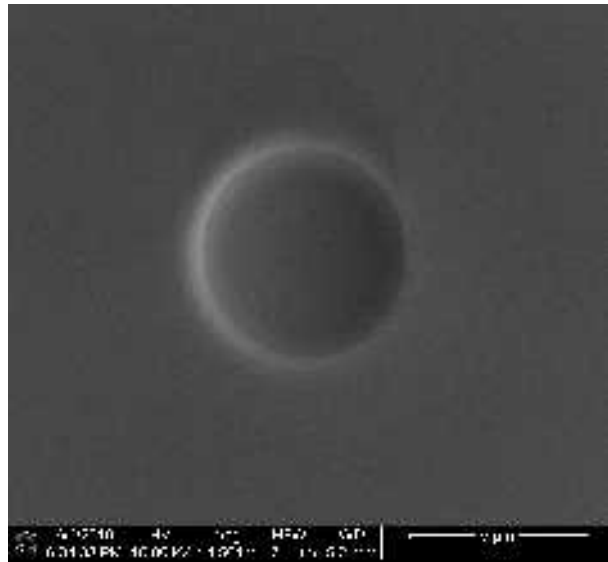
Glucoza in apă



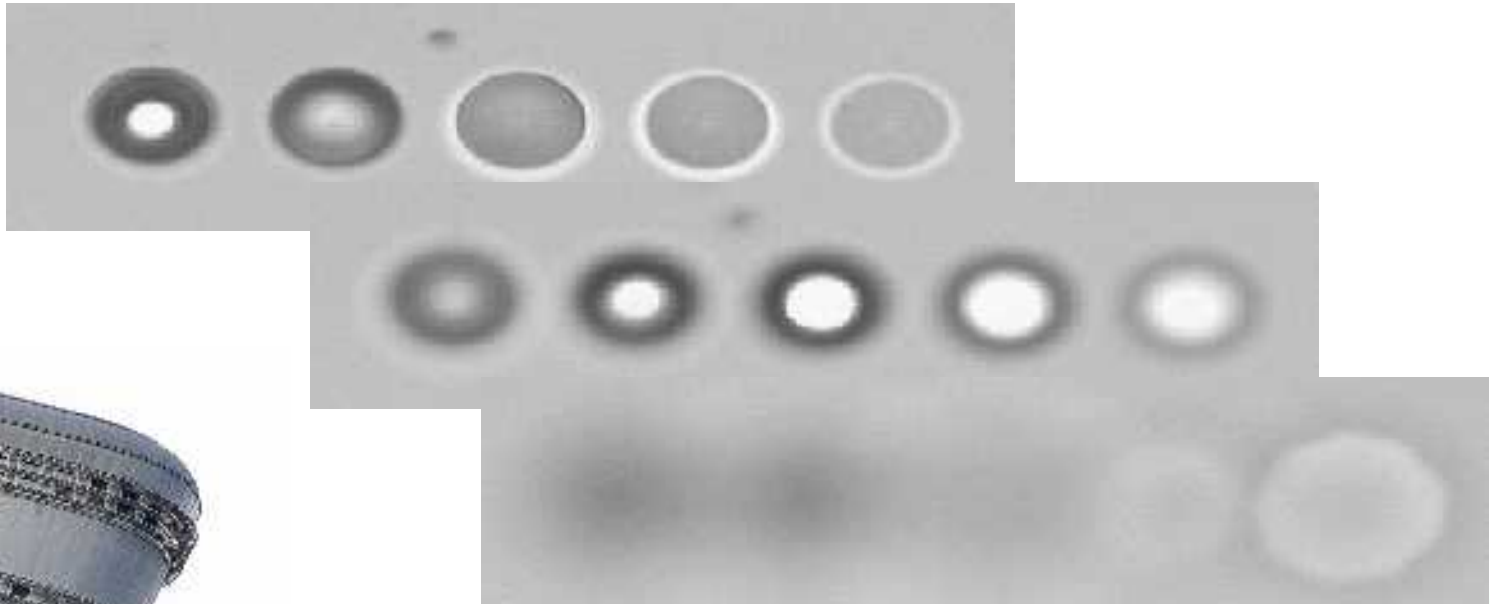
Concentrori parabolici



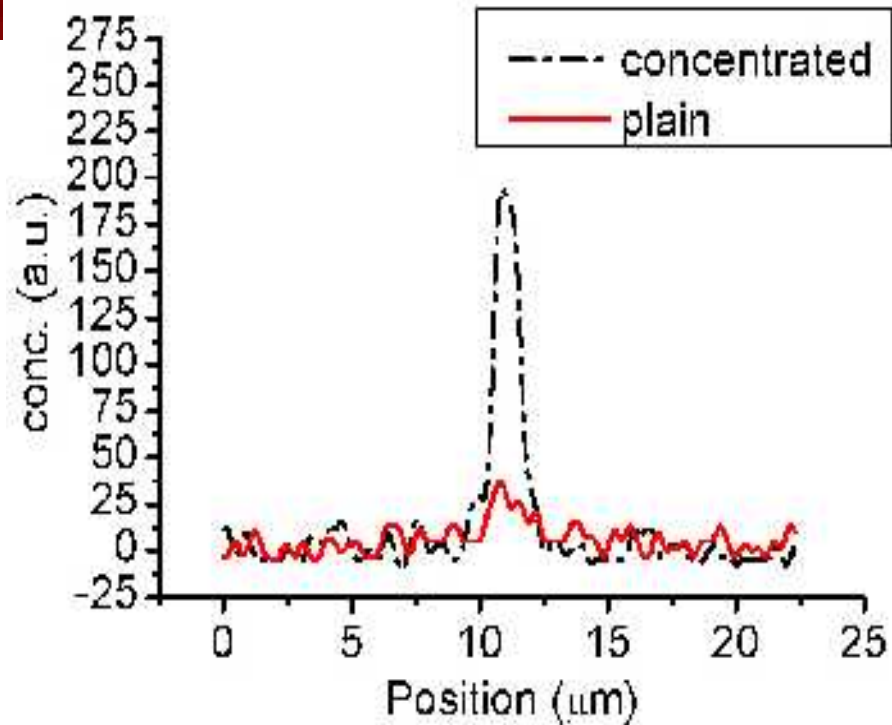
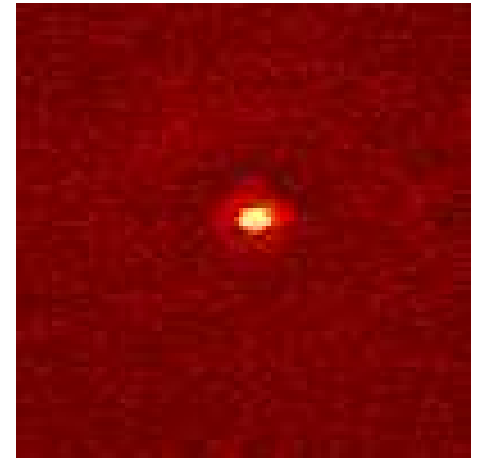
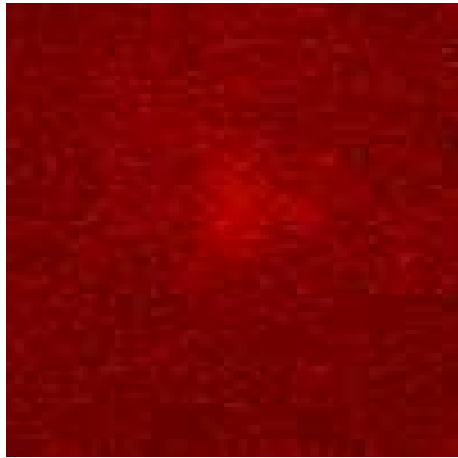
Controlul dozei si al fascicului de ioni



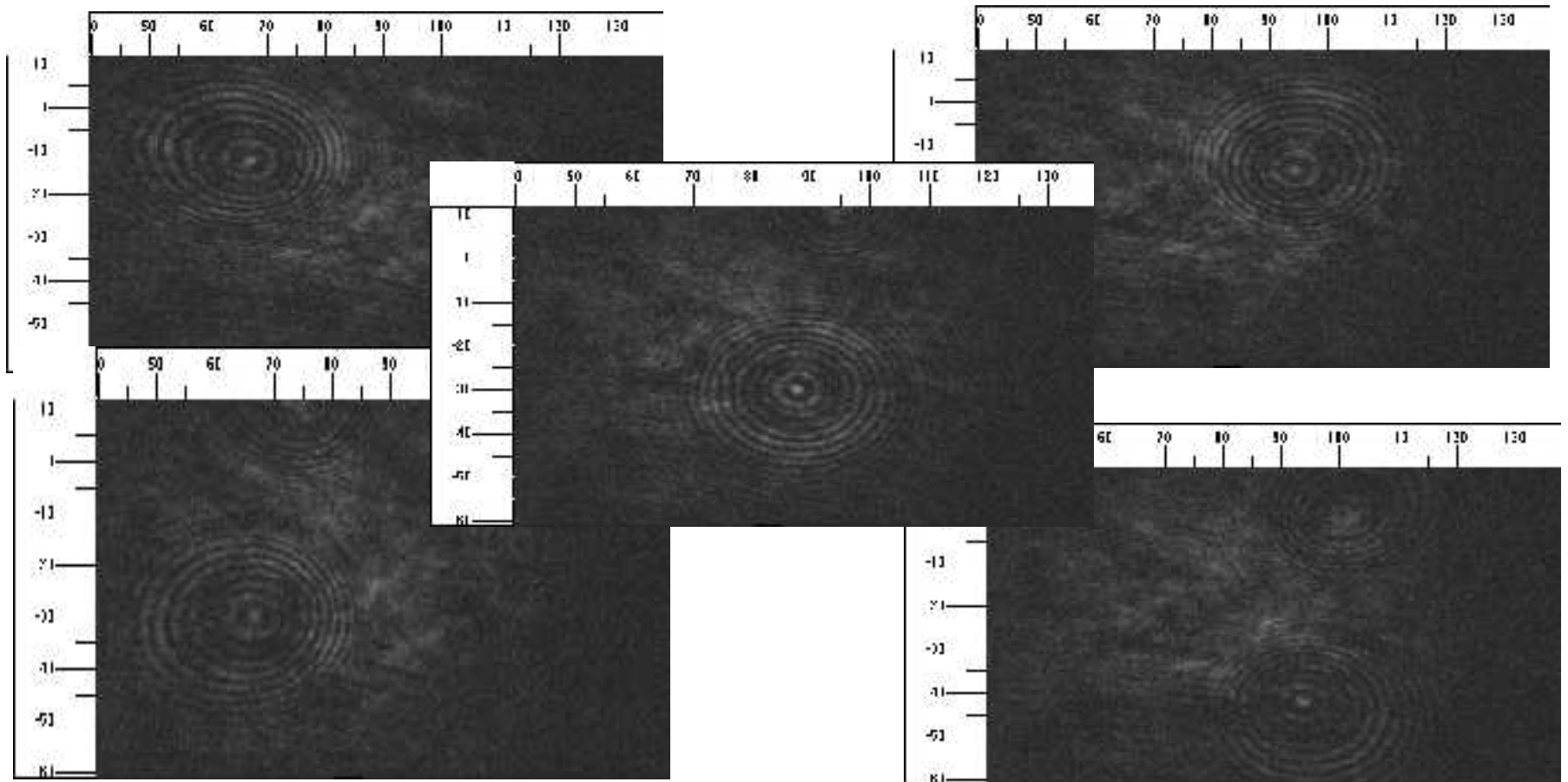
- Eficienți la iluminare redusă
- Cresc eficiența de colectare/detectare (semnalul $\sim X+A \ln X$) și unghiul solid de colectare $[d^2\sigma/(dEd\Omega)]$
- Nu se substituie SERS.

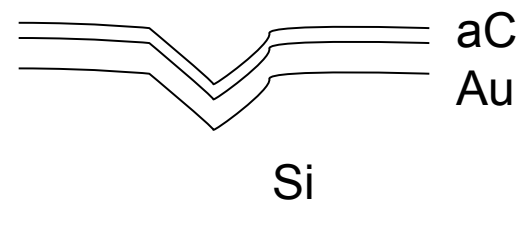
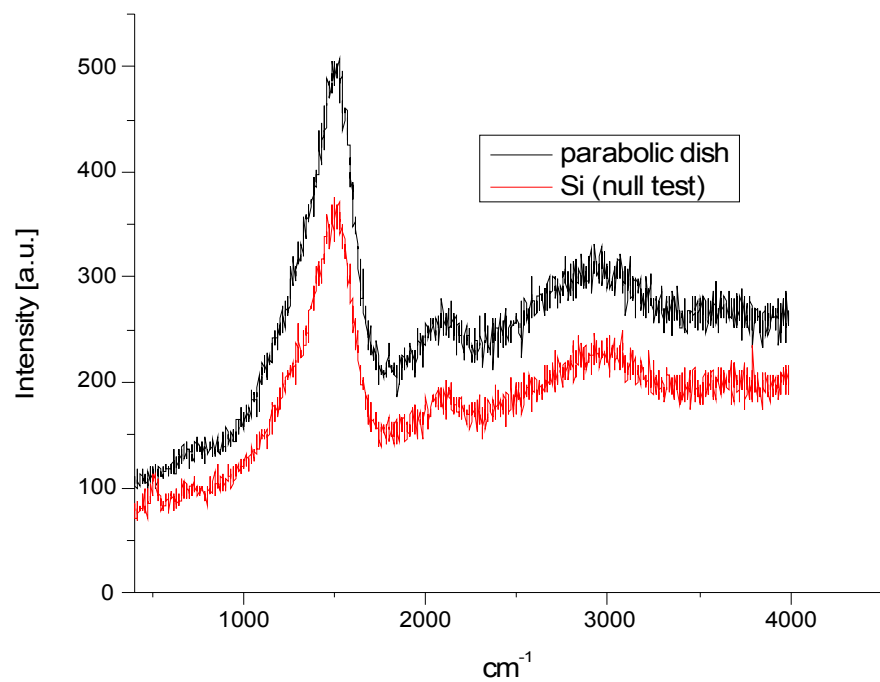


Concentrioni

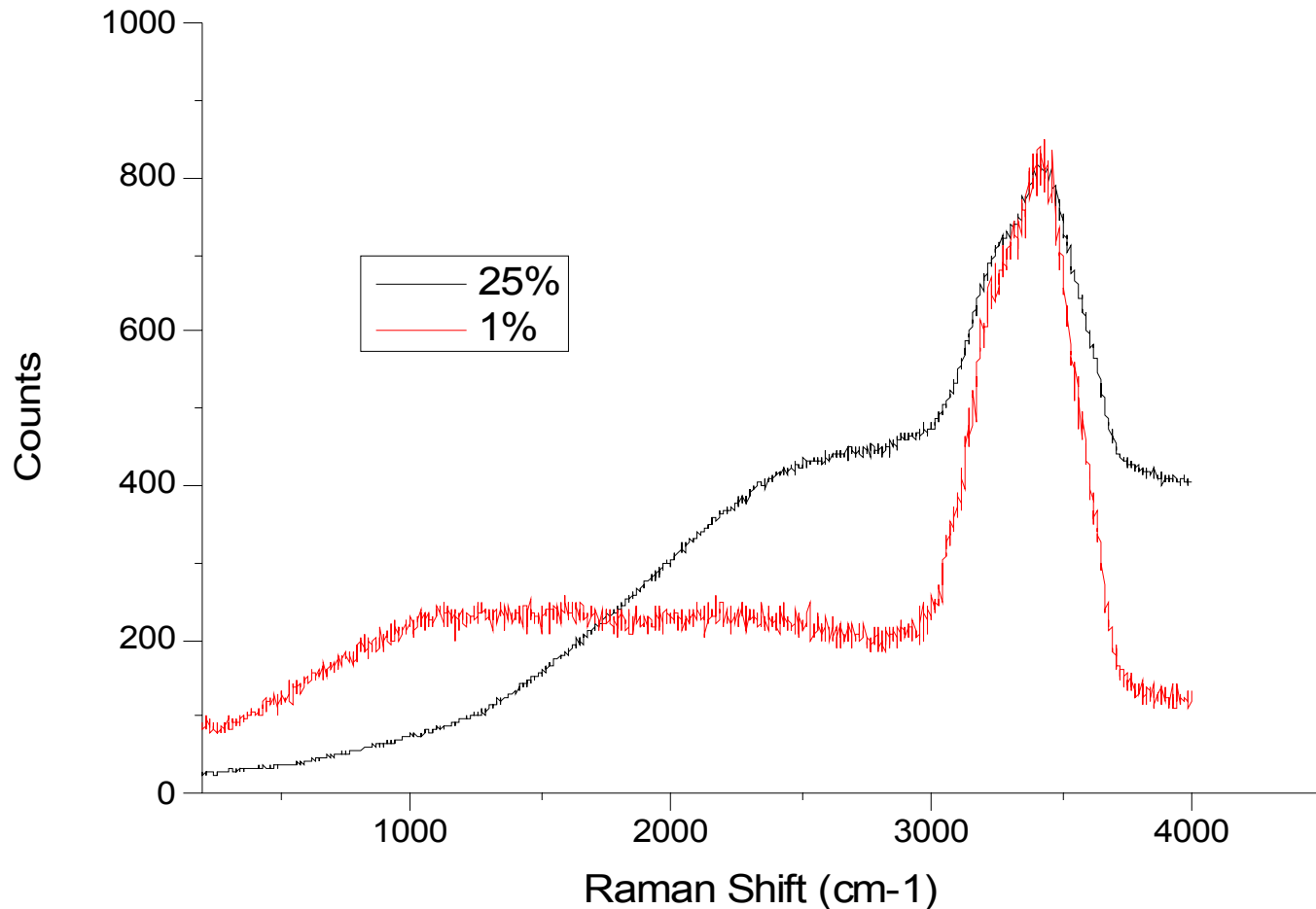


Microscopul Raman (aberratii sferice)

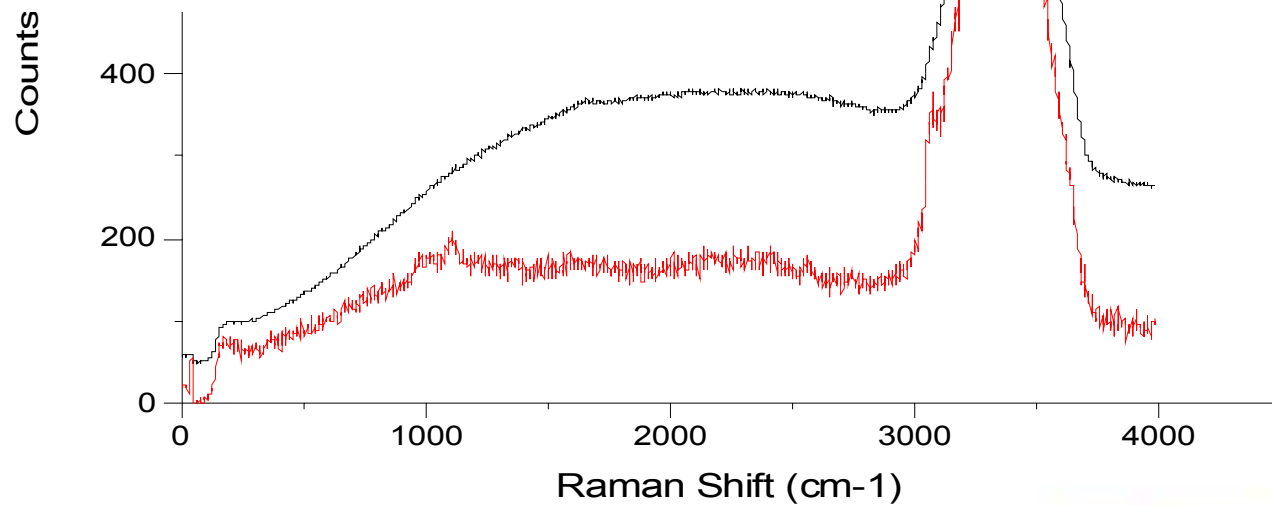
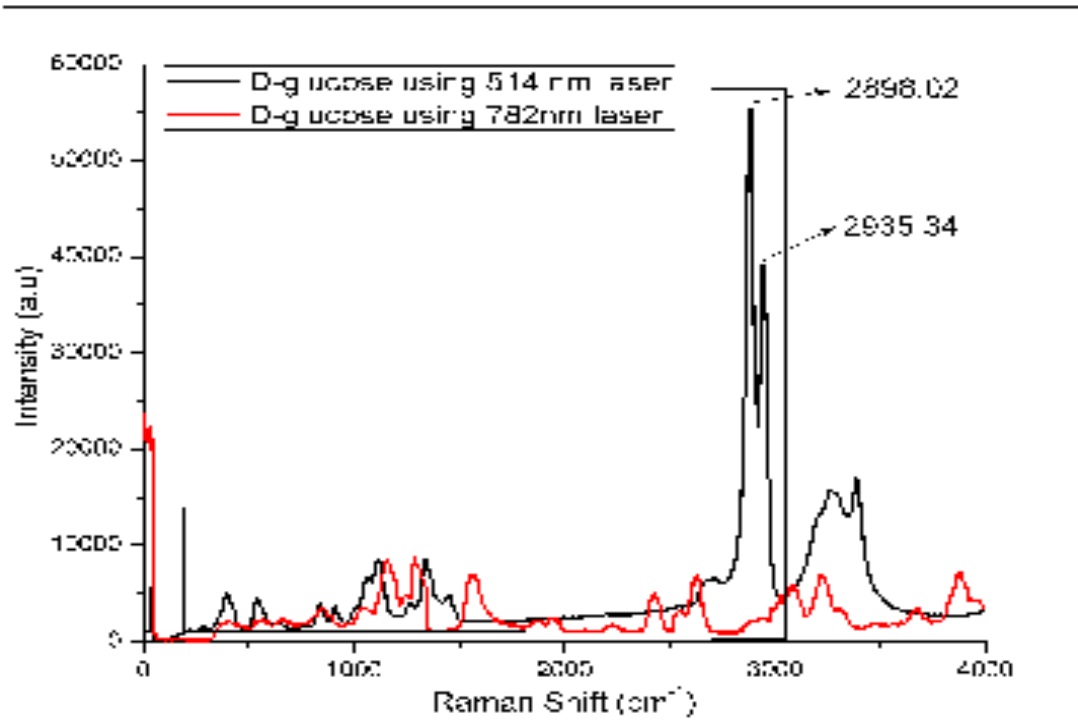




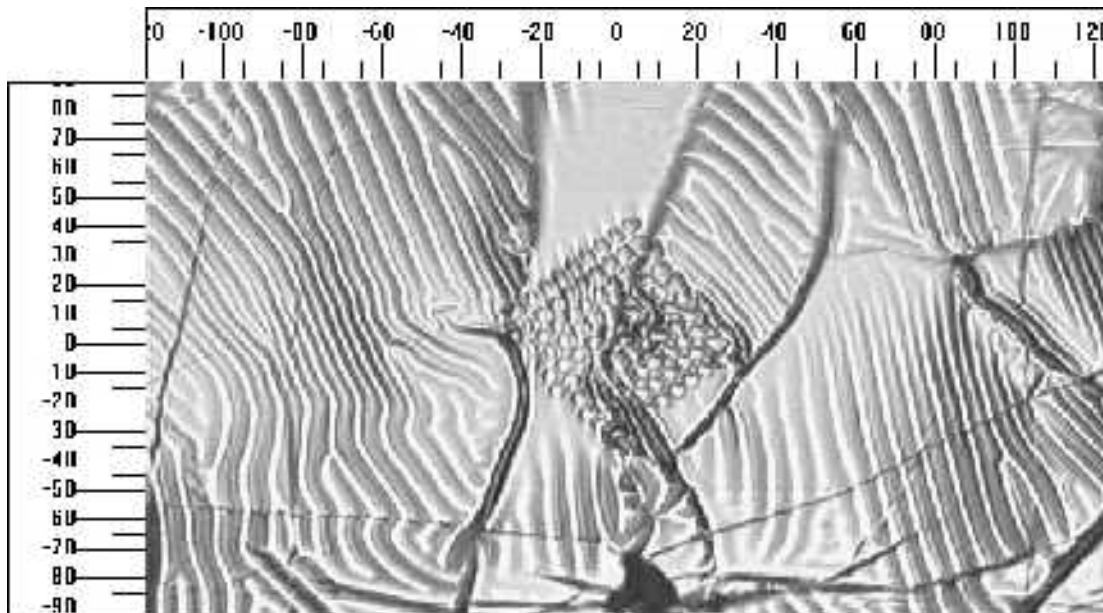
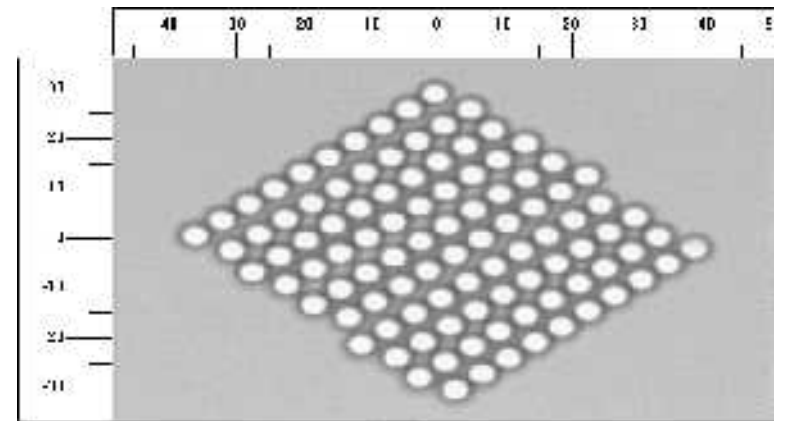
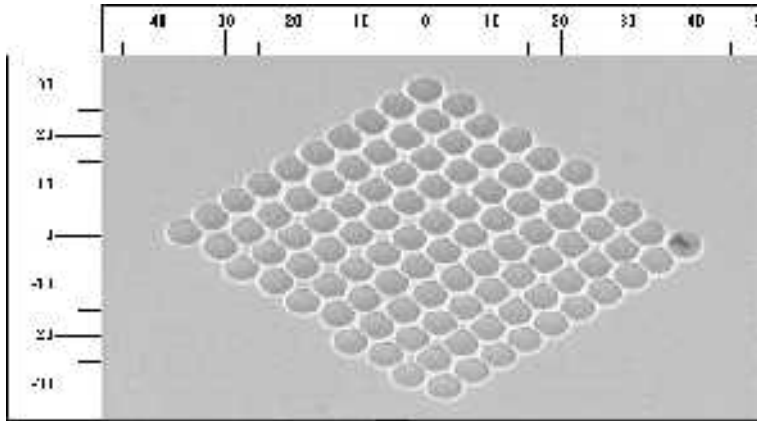
Spectru Raman la intensitate mică (Laser =
532nm) -test nul (pe suprafață plată)
 1×10^{-3} g/ml



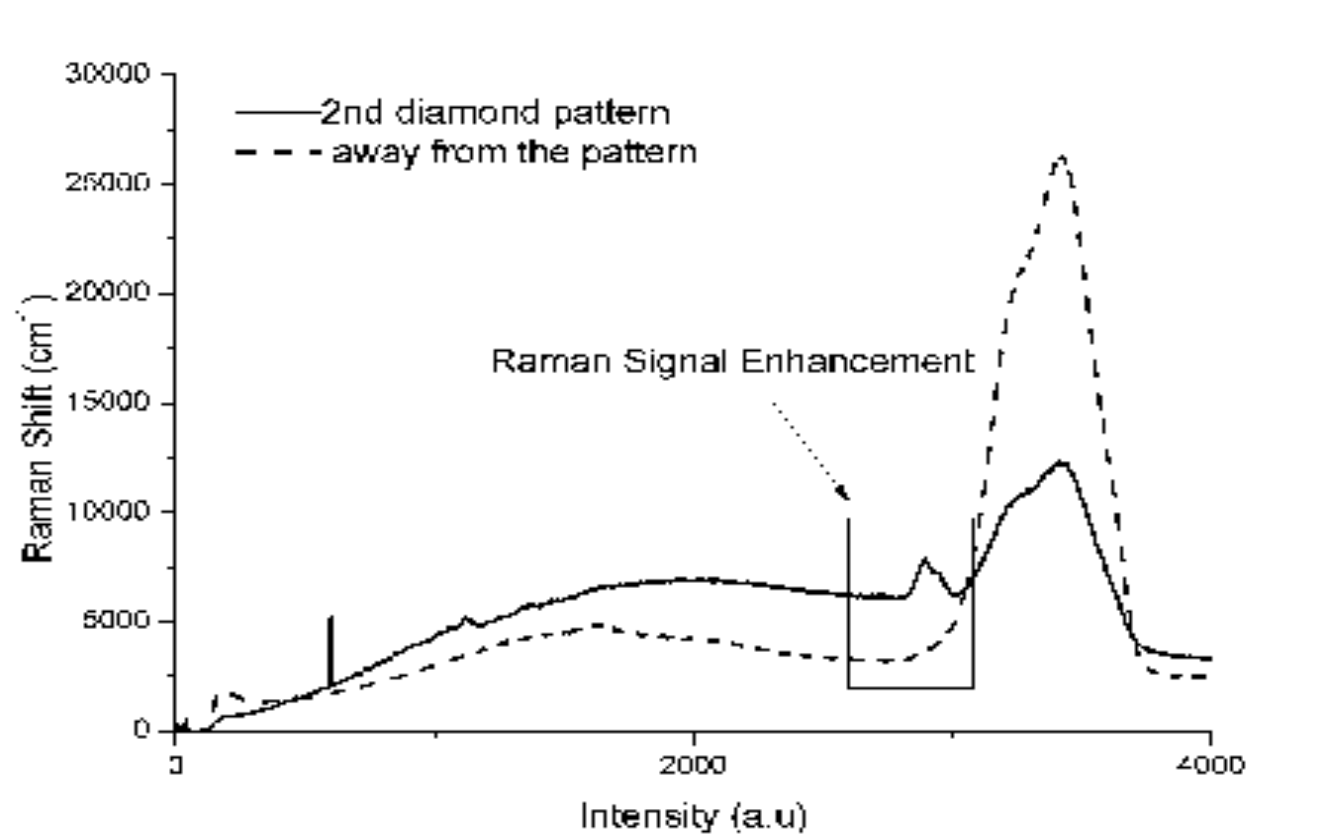
Concentratori: 1×10^{-3} g/ml



Rezultate (preliminare) pe glucoză



SERS (Au), green laser, 5×10^{-3} g/ml



Concluzii

Concentrorii par să amplifice semnalul Raman. O interpretare este creșterea unghiului solid de colectare a semnalului. SERS necesar.

Recipient 'ideal' pentru lichide; Efecte optice reproductibile.

- Modificarea aperturii optice poate demonstra această teorie
 - (aproape) totul e posibil cu FIB, dar serial (încet).
- Microscopie electronica
 - EELS cu rezoluție sub-nanometrică.



